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Application/Con	trol No.	Applicant(s) Reexaminat	/Patent under ion
10/797,824		CHAO ET A	AL.
Examiner		Art Unit	
Charles R. Kase	enge	2125	

	SEAR	CHED	
Class	Subclass	Date	Examiner
700	99	7/7/2005	ск
	100		
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
700	121	1/10/2006	СК	
	112			
	ttached ice Search	1/10/2006	ск	

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
Updated EAST; terms: ((replac\$3 (back adj up) backup substitut\$3) near2 (wafer workpiece substrate)) same (metal adj layer\$3)	1/10/2006	СК
Inventor and Assignee Search	1/10/2006	CK